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8	457	((threadlike or thread\$like) with struct\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/18 12:24
15	248	((threadlike or thread\$like) near struct\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/18 12:24
29	1	((threadlike or thread\$like) near struct\$4)) same (parent\$3 or child\$5 or ancest\$3 or father\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/18 12:26
36	0	((threadlike or thread\$like) near struct\$4)) same (calculat\$4 near3 intens\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/18 12:27
43	9	((threadlike or thread\$like) near struct\$4)) same (intens\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/18 12:27
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